

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/017,186	<b>Applicant(s)/Patent under Reexamination</b>  FARIS, SADEG M.
	<b>Examiner</b>  PAUL T. CHIN	<b>Art Unit</b>  3652

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner